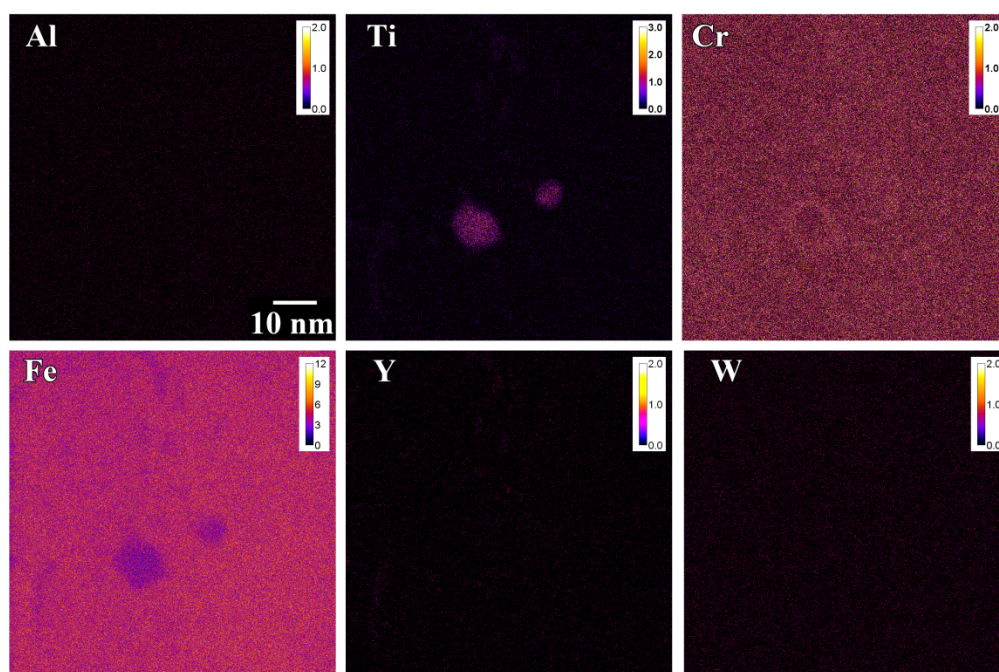


**Online supplementary information for:** Aberration-corrected X-ray spectrum imaging and Fresnel contrast to differentiate nanoclusters and cavities in helium-irradiated alloy 14YWT

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*Figure Supplementary S5: Raw X-ray count maps for the data presented in Figure 5.*

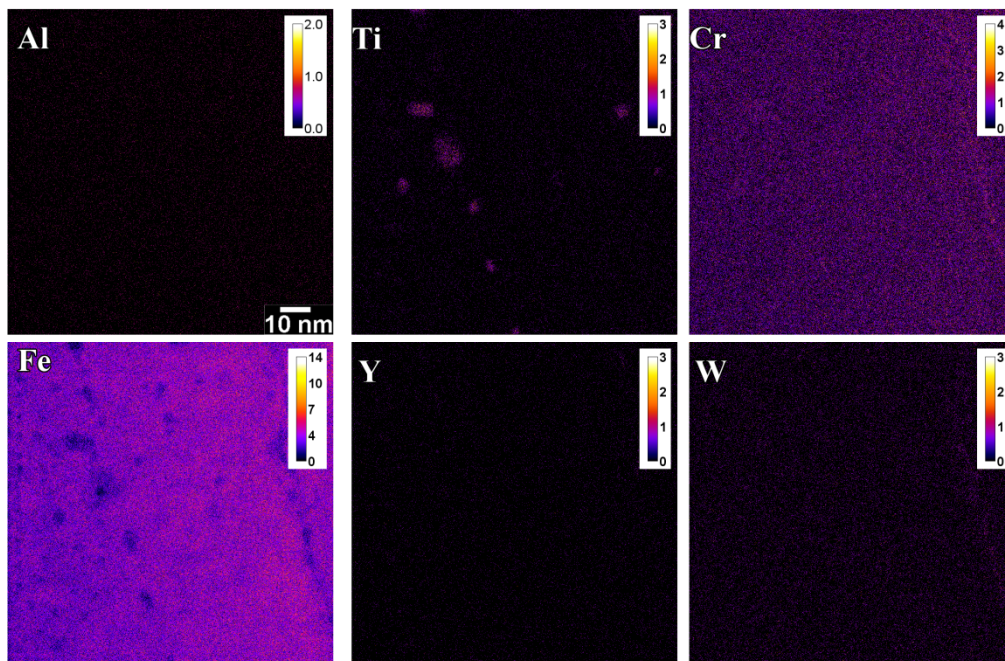


Figure Supplementary S6: Raw X-ray count maps for the data presented in Figure 6.

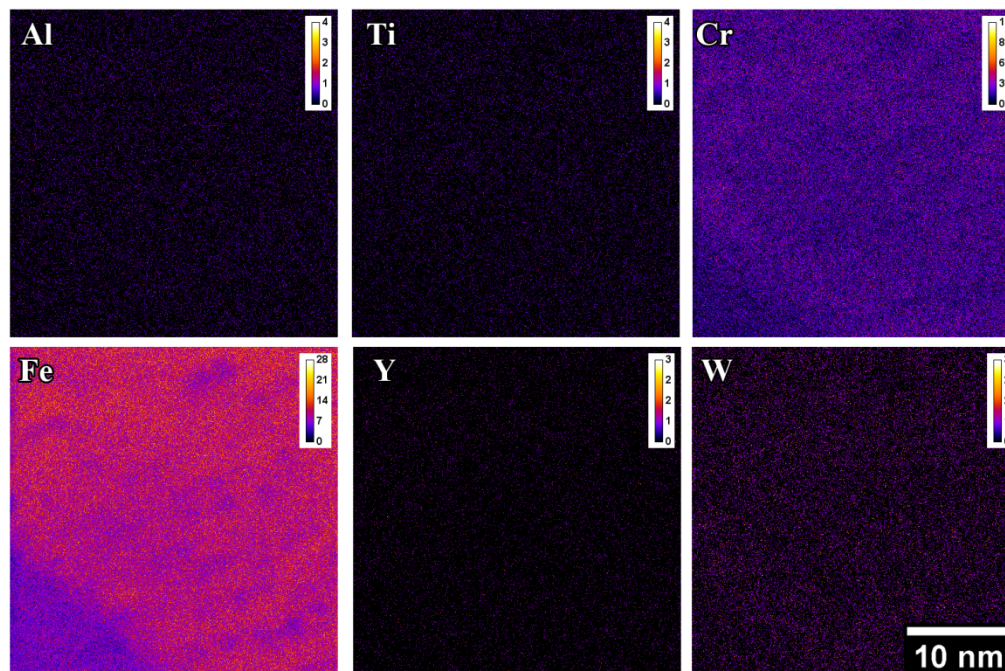


Figure Supplementary S9: Raw X-ray count maps for the data presented in Figure 9.